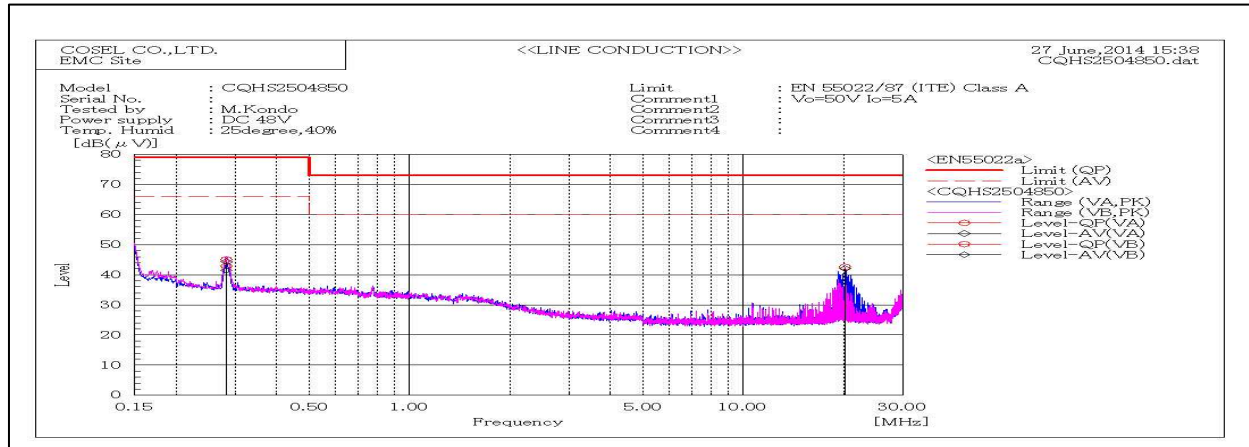
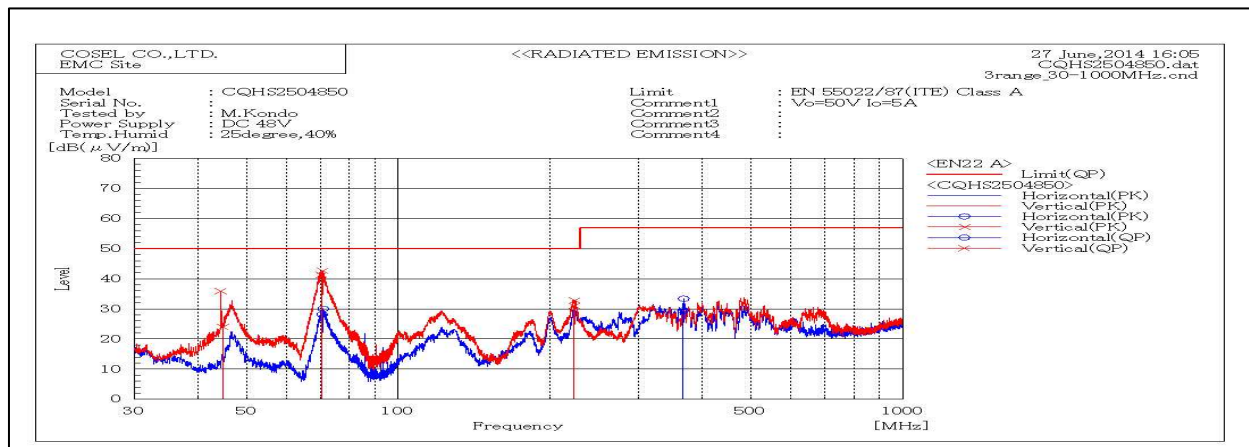


DATA SHEET		Date	27-Jun-14
Model	CQHS2504850	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo



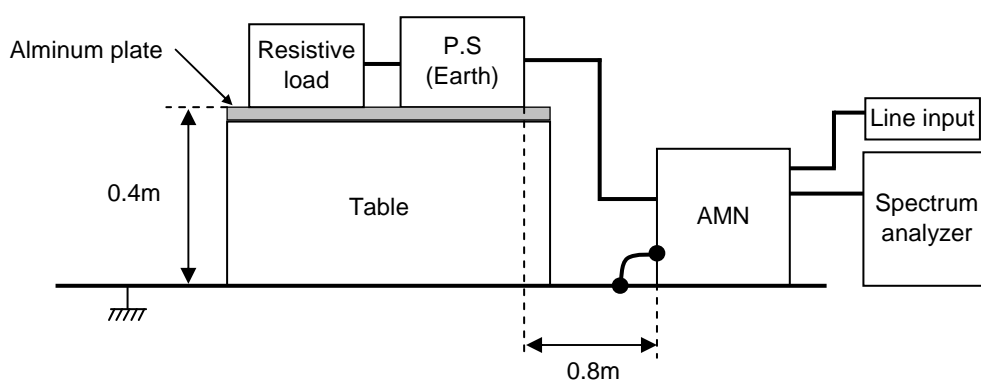
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.2827		VA	22.8	21.4	20.1	42.9	41.5	79	66	36.1	24.5	Pass	
0.28271		VB	25	24.2	20.1	45.1	44.3	79	66	33.9	21.7	Pass	
20.1847		VA	21.6	21.1	21	42.6	42.1	73	60	30.4	17.9	Pass	



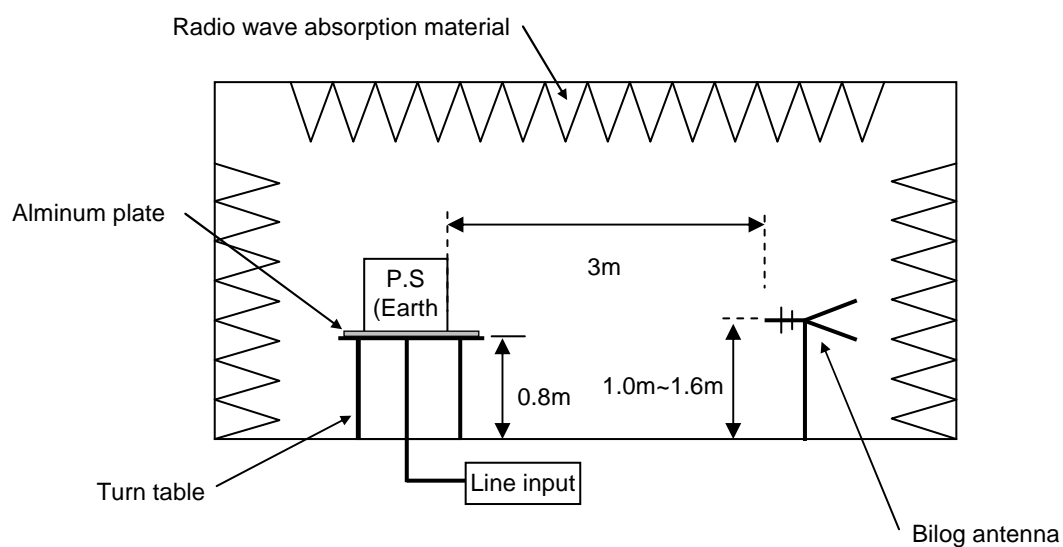
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
44.91	V	Stable	43.5		-19.5	24	50	26	Pass	105	76	
70.423	V	Stable	61.9		-20.6	41.3	50	8.7	Pass	107	101	
70.694	H	Stable	53.8		-25.6	28.2	50	21.8	Pass	157	352	
223.177	V	Stable	46		-15	31	50	19	Pass	139	291	
367.046	H	Stable	41.8		-12.4	29.4	57	27.6	Pass	120	109	

DATA SHEET		Date	27-Jun-14
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo

1. Line conduction



2. Radiated emission

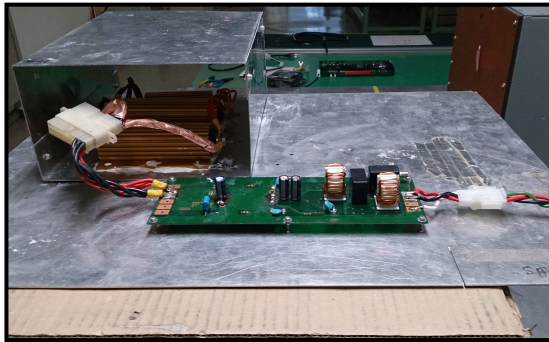


Test: EMI

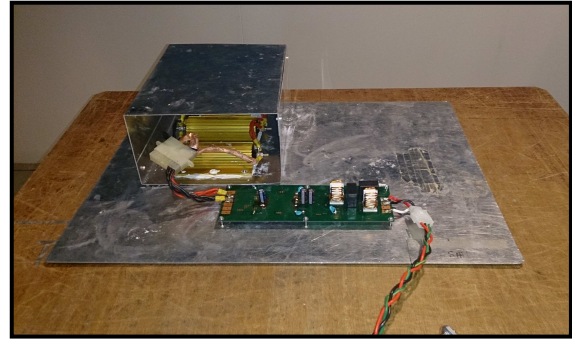
Model Name: CQHS250 Series

○ Photographs of Test Set-Up

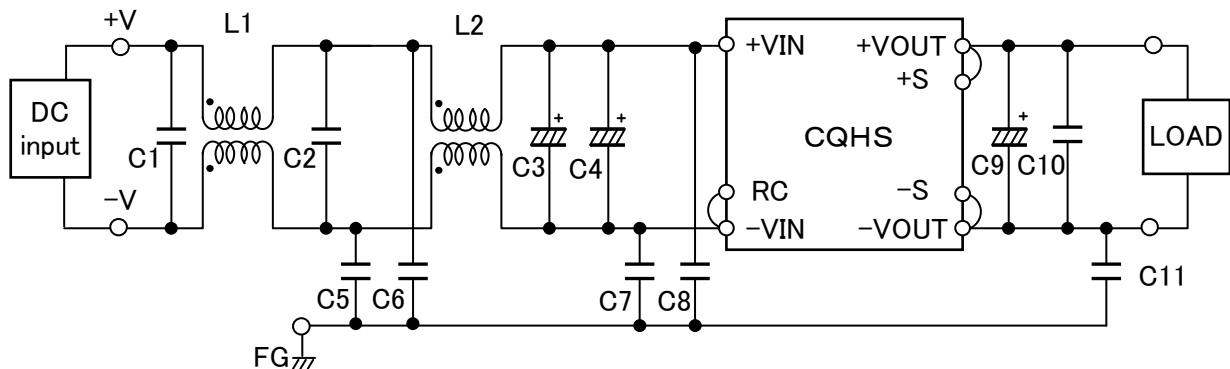
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1, L2 : 0.5mH 15A Inductor (SC-15-05J NEC TOKIN)
- C1, C2 : 310V 2.2 μ F Film capacitor (OKAYA ELEC)
- C3, C4 : 100V 68 μ F Electlic capacitor (LXV NIPPON CHEMI-CON)
- C5, C6, C7, C8 : 250V 4700pF Ceramic capacitor (Type KY MURATA)
- C9 : CQHS2504832 50V 220 μ F Electlic capacitor (LXZ NIPPON CHEMI-CON)
- C10 : CQHS2504850 100V 100 μ F Electlic capacitor (KY NIPPON CHEMI-CON)
- C11 : 630V 0.068 μ F Film capacitor (NITSUKO)